

FQPF8N80C-VB Datasheet

N-Channel 800V (D-S) Super Junction Power MOSFET

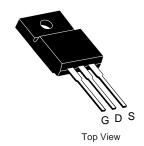
PRODUCT SUMI	MARY	
V _{DS} (V)	800)
R _{DS(on)} (Ω)	V _{GS} = 10 V	1.2
Q _g (Max.) (nC)	200)
Q _{gs} (nC)	24	
Q _{gd} (nC)	110)
Configuration	Sing	le

FEATURES

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Isolated Central Mounting Hole
- · Fast Switching
- Ease of Paralleling
- Simple Drive Requirements
- Compliant to RoHS Directive 2002/95/EC









ABSOLUTE MAXIMUM RATINGS (T_C	= 25 °C, unl	ess otherwis	se noted)			
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V _{DS}	800	V	
Gate-Source Voltage		V_{GS}	± 30	1 V		
Continuous Drain Current	V _{GS} at 10 V	T _C = 25 °C	I_	5		
Continuous Diain Current	VGS at 10 V	T _C = 100 °C	I _D	3.9	Α	
Pulsed Drain Current ^a	•	•	I _{DM}	21		
Linear Derating Factor				1.5	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	770	mJ	
Repetitive Avalanche Currenta			I _{AR}	7.8	А	
Repetitive Avalanche Energy ^a			E _{AR}	19	mJ	
Maximum Power Dissipation	T _C =	25 °C	P _D	190	W	
Peak Diode Recovery dV/dt ^c		dV/dt	2.0	V/ns		
Operating Junction and Storage Temperature Range			T _J , T _{stg}	- 55 to + 150	°C	
Soldering Recommendations (Peak Temperature)	for	10 s		300 ^d	1	
Mounting Toyour	6-32 or M3 screw			10	lbf ⋅ in	
Mounting Torque	6-32 or i	vio screW		1.1	N⋅m	

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. V_{DD} = 50 V, starting T_J = 25 °C, L = 23 mH, R_g = 25 Ω , I_{AS} = 7.8 A (see fig. 12). c. I_{SD} \leq 7.8 A, dl/dt \leq 140 A/ μ s, V_{DD} \leq 600 V, T_J \leq 150 °C.

^{*} Pb containing terminations are not RoHS compliant, exemptions may apply



THERMAL RESISTANCE RAT	INGS			
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R _{thJA}	-	40	
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.24	-	°C/W
Maximum Junction-to-Case (Drain)	R _{thJC}	-	0.65	

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static						,	
Drain-Source Breakdown Voltage	V _{DS}	V _{GS}	= 0 V, I _D = 250 μA	800	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	e to 25 °C, I _D = 1 mA	-	0.98	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} :	= V _{GS} , I _D = 250 μA	2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}		V _{GS} = ± 20 V	-	-	± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}		= 800 V, V _{GS} = 0 V V, V _{GS} = 0 V, T _J = 125 °C	-	-	100 500	μΑ
Drain-Source On-State Resistance	R _{DS(on)}		$I_D = 3.7 \text{ A}^b$	-	1.2	-	Ω
Forward Transconductance	9fs		= 100 V, I _D = 3.7 A ^b	5.6	-	-	S
Dynamic	<u> </u>		_	L			
Input Capacitance	C _{iss}	V 0V		-	3100	-	pF
Output Capacitance	C _{oss}	1	$V_{GS} = 0 \text{ V},$ $V_{DS} = 25 \text{ V},$		800	-	
Reverse Transfer Capacitance	C _{rss}	f = 1.0 MHz, see fig. 5		-	490	-	
Total Gate Charge	Qg		I _D = 3.8 A, V _{DS} = 400 V, see fig. 6 and 13 ^b	-	-	200	nC
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V		-	-	24	
Gate-Drain Charge	Q_{gd}			-	-	110	
Turn-On Delay Time	$t_{d(on)}$	V_{DD} = 400 V, I_{D} = 3.8 A, R_{g} = 6.2 Ω , R_{D} = 52 Ω see fig. 10 ^b		-	19	-	ns
Rise Time	t _r			-	38	-	
Turn-Off Delay Time	$t_{d(off)}$			-	120	-	
Fall Time	t _f			-	39	-	
Internal Drain Inductance	L_D	Between lead, 6 mm (0.25") from package and center of die contact		-	5.0	-	ml l
Internal Source Inductance	L _S			-	13	-	- nH
Drain-Source Body Diode Characteristic	s					•	
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	5.0	_
Pulsed Diode Forward Current ^a	I _{SM}			-	-	21	A
Body Diode Voltage	V _{SD}	T _J = 25 °C, I _S = 3.8 A, V _{GS} = 0 V ^b		-	-	1.8	V
Body Diode Reverse Recovery Time	t _{rr}	T _J = 25 °C, I _F = 3.8 A, dl/dt = 100 A/ μ s ^b		-	650	980	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	3.8	5.7	μC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L _S and				L _D)	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Pulse width \leq 300 µs; duty cycle \leq 2 %.



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

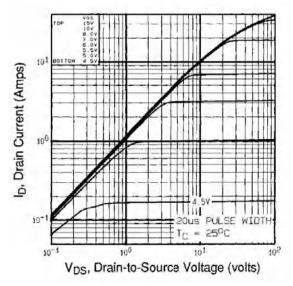


Fig. 1 - Typical Output Characteristics, T_C = 25 °C

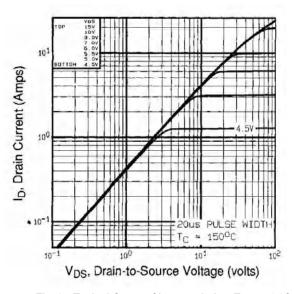


Fig. 2 - Typical Output Characteristics, T_C = 150 °C

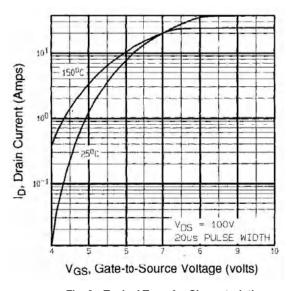


Fig. 3 - Typical Transfer Characteristics

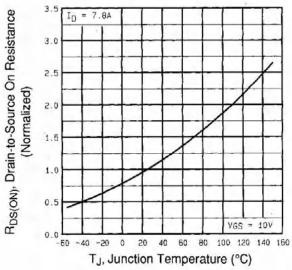


Fig. 4 - Normalized On-Resistance vs. Temperature



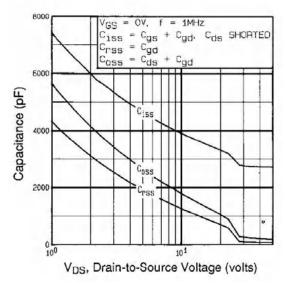


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

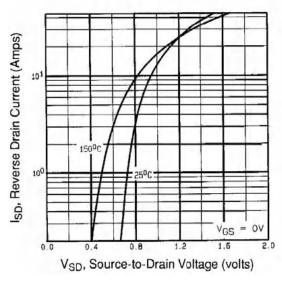


Fig. 7 - Typical Source-Drain Diode Forward Voltage

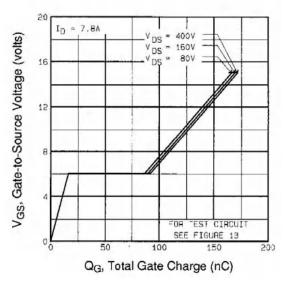


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

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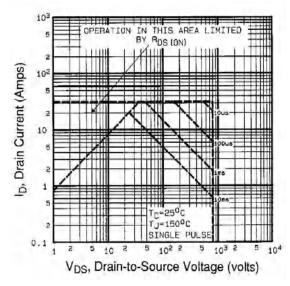


Fig. 8 - Maximum Safe Operating Area



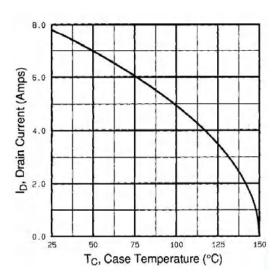


Fig. 9 - Maximum Drain Current vs. Case Temperature

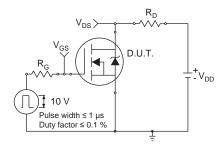


Fig. 10a - Switching Time Test Circuit

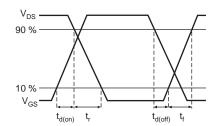


Fig. 10b - Switching Time Waveforms

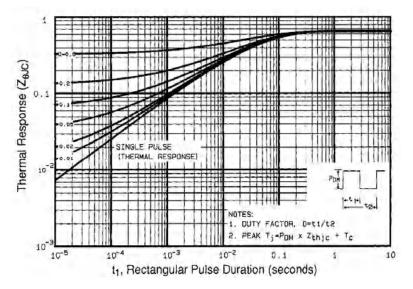


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case



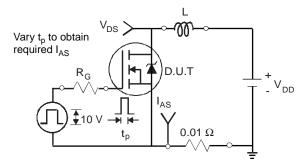


Fig. 12a - Unclamped Inductive Test Circuit

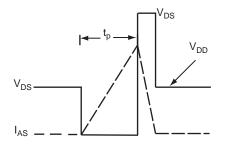


Fig. 12b - Unclamped Inductive Waveforms

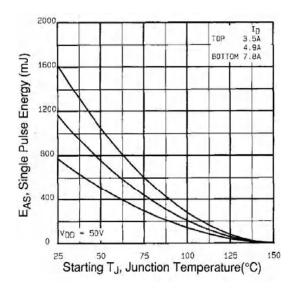


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

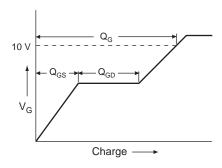


Fig. 13a - Basic Gate Charge Waveform

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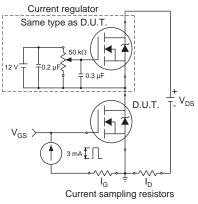
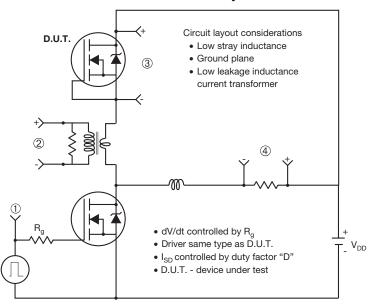


Fig. 13b - Gate Charge Test Circuit



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Peak Diode Recovery dV/dt Test Circuit



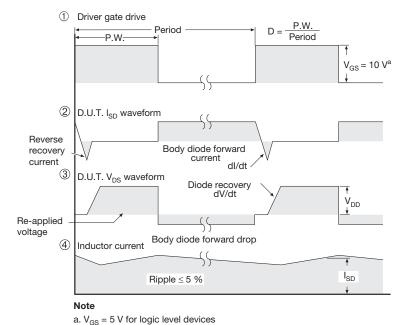
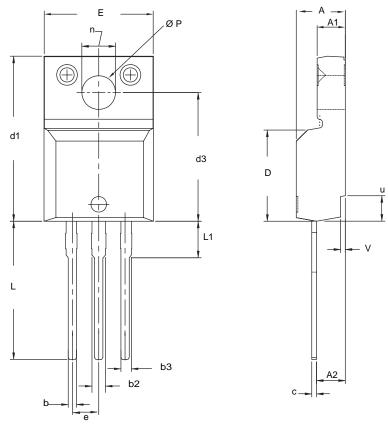


Fig. 14 - For N-Channel



TO-220 FULLPAK (HIGH VOLTAGE)



DIM.	MILLIMETERS		INC	HES
	MIN.	MAX.	MIN.	MAX.
Α	4.570	4.830	0.180	0.190
A1	2.570	2.830	0.101	0.111
A2	2.510	2.850	0.099	0.112
b	0.622	0.890	0.024	0.035
b2	1.229	1.400	0.048	0.055
b3	1.229	1.400	0.048	0.055
С	0.440	0.629	0.017	0.025
D	8.650	9.800	0.341	0.386
d1	15.88	16.120	0.622	0.635
d3	12.300	12.920	0.484	0.509
Е	10.360	10.630	0.408	0.419
е	2.54	BSC	0.100	BSC
L	13.200	13.730	0.520	0.541
L1	3.100	3.500	0.122	0.138
n	6.050	6.150	0.238	0.242
ØΡ	3.050	3.450	0.120	0.136
u	2.400	2.500	0.094	0.098
V	0.400	0.500	0.016	0.020

DWG: 5972

Notes

- To be used only for process drawing.
 These dimensions apply to all TO-220, FULLPAK leadframe versions 3 leads.
 All critical dimensions should C meet C_{pk} > 1.33.
 All dimensions include burrs and plating thickness.
 No chipping or package damage.



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